

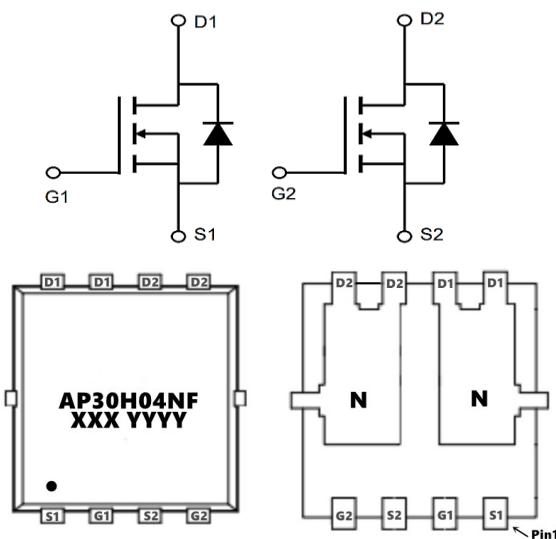
Description

The AP30H04NF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 40V$ $I_D = 30A$

$R_{DS(ON)} < 14m\Omega$ @ $V_{GS}=10V$ (**Type: 11mΩ**)

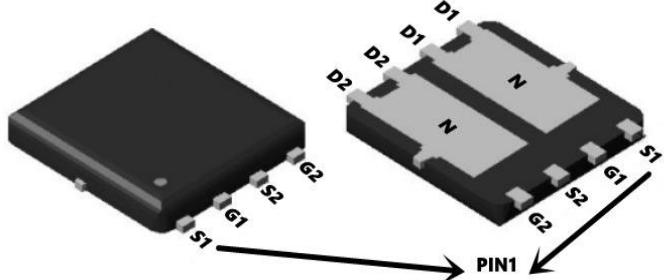


Application

Wireless charging

Boost driver

Brushless motor



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP30H04NF	PDFN5*6-8L	AP30H04NF XXX YYYY	5000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	40	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_A=25^\circ C$	Continuous Drain Current ¹	30	A
$I_D@T_A=70^\circ C$	Continuous Drain Current ¹	21	A
IDM	Pulsed Drain Current ²	36	A
EAS	Single Pulse Avalanche Energy ³	31	mJ
I_{AS}	Avalanche Current	25	A
$P_D@T_A=25^\circ C$	Total Power Dissipation ⁴	1.9	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹ ($t \leq 10s$)	25	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-ambient ¹	8	°C/W

40V N+N-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	40	44	---	V
$\Delta BVDSS/\Delta TJ$	BVDSS Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	---	0.034	---	$\text{V}/^\circ\text{C}$
RDS(ON)	Static Drain-Source On-Resistance ²	$V_{GS}=10\text{V}$, $I_D=8\text{A}$	---	11	14	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=6\text{A}$	---	13	18	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	1.0	1.6	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	-5.64	---	$\text{mV}/^\circ\text{C}$
IDSS	Drain-Source Leakage Current	$V_{DS}=32\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	uA
		$V_{DS}=32\text{V}$, $V_{GS}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	---	---	± 100	nA
gfs	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=8\text{A}$	---	36	---	S
R _g	Gate Resistance	$V_{DS}=0\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	2.1	---	Ω
Q _g	Total Gate Charge (4.5V)	$V_{DS}=20\text{V}$, $V_{GS}=4.5\text{V}$, $I_D=8\text{A}$	---	10.7	---	nC
Qgs	Gate-Source Charge		---	3.3	---	nC
Qgd	Gate-Drain Charge		---	4.2	---	nC
Td(on)	Turn-On Delay Time	$V_{DD}=12\text{V}$ $V_{GS}=10\text{V}$ $R_G=3.3\Omega$ $I_D=6\text{A}$	---	8.6	---	ns
T _r	Rise Time		---	3.4	---	ns
Td(off)	Turn-Off Delay Time		---	24.8	---	ns
T _f	Fall Time		---	2.2	---	ns
C _{iss}	Input Capacitance	$V_{DS}=15\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	1314	---	pF
C _{oss}	Output Capacitance		---	120	---	
C _{rss}	Reverse Transfer Capacitance		---	88	---	
IS	Continuous Source Current ^{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	8.5	A
ISM	Pulsed Source Current ^{2,5}		---	---	34	A
VSD	Diode Forward Voltage ²	$V_{GS}=0\text{V}$, $I_S=1\text{A}$, $T_J=25^\circ\text{C}$	---	---	1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3、EAS condition: $TJ=25^\circ\text{C}$, $VDD=32\text{V}$, $VGS=10\text{V}$, $L=0.1\text{Mh}$, $IAS=22\text{A}$
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

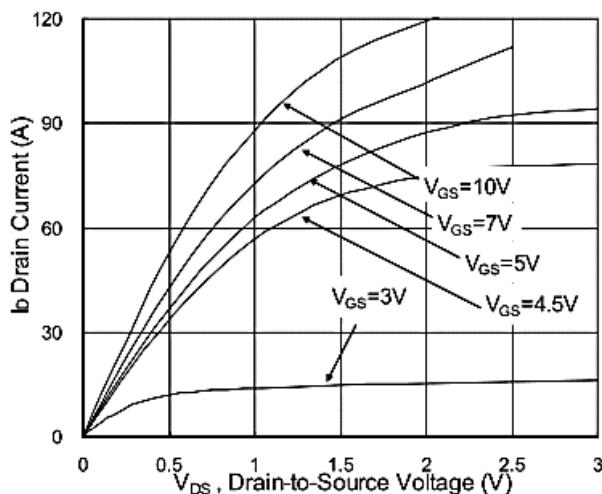


Fig.1 Typical Output Characteristics

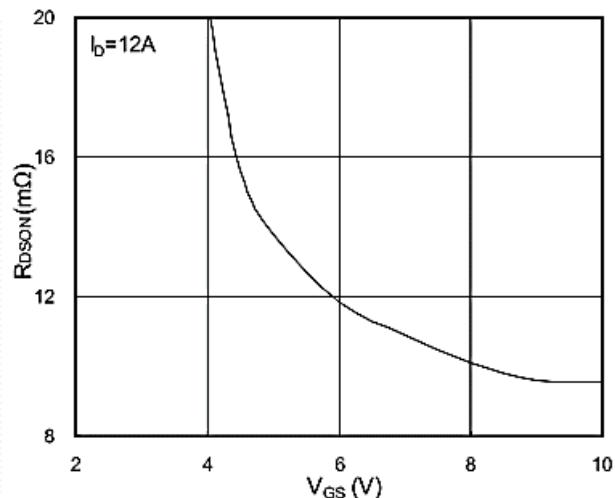


Fig.2 On-Resistance vs. G-S Voltage

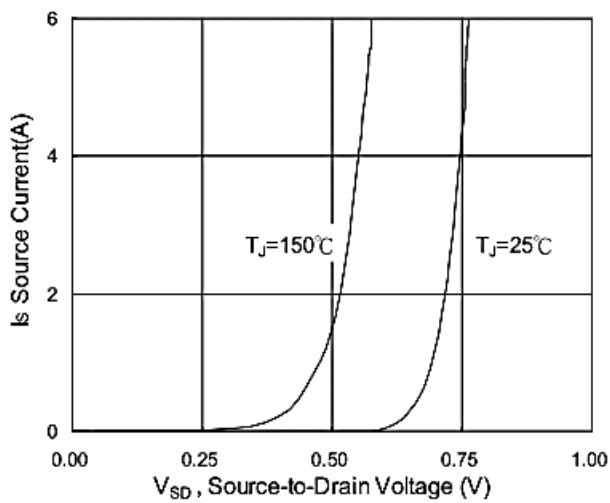


Fig.3 Forward Characteristics of Reverse

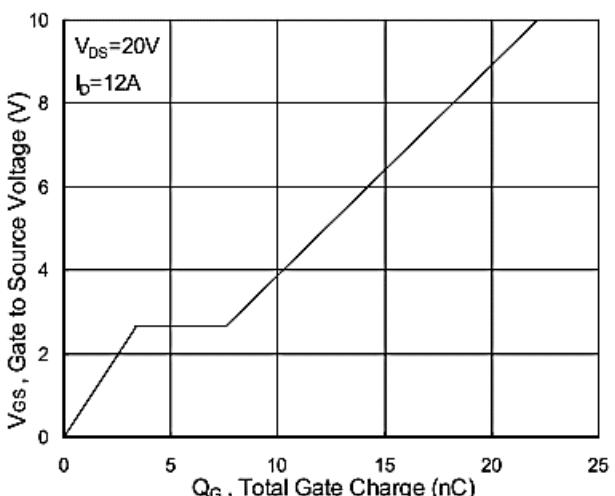


Fig.4 Gate-Charge Characteristics

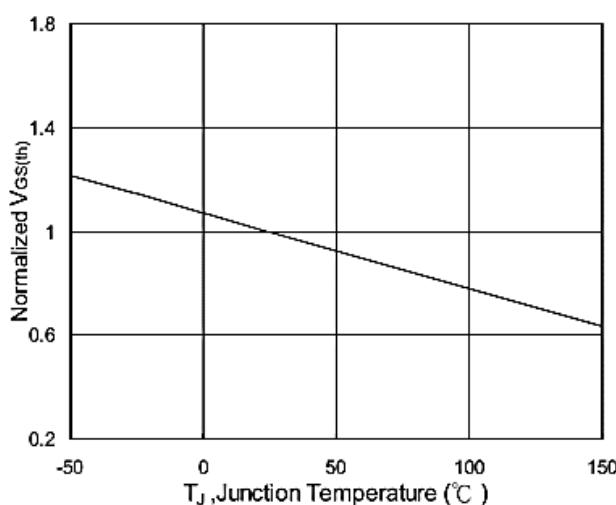


Fig.5 $V_{GS(th)}$ vs. T_J

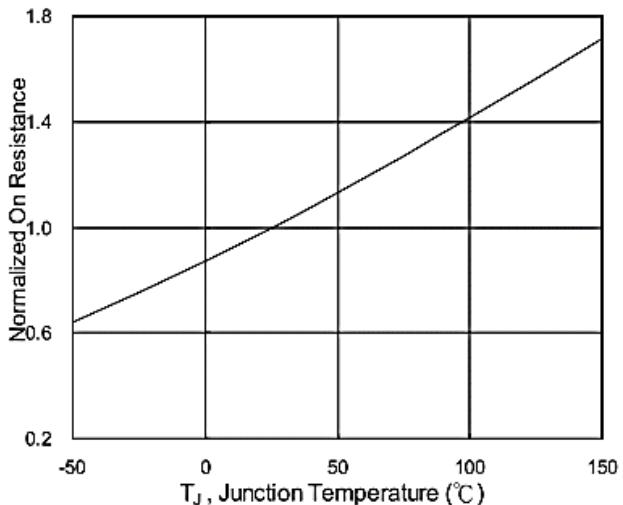
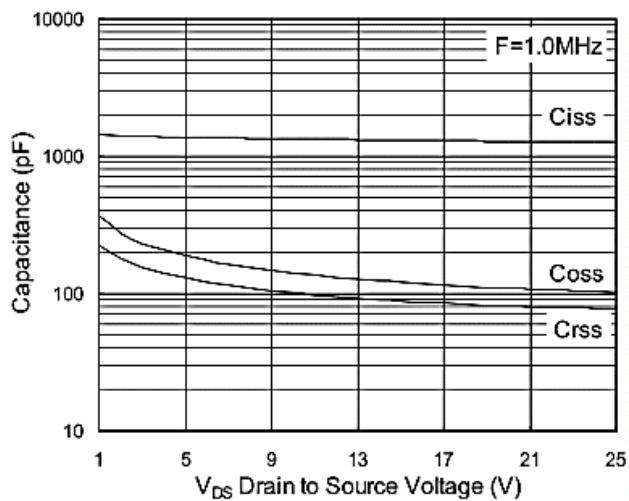
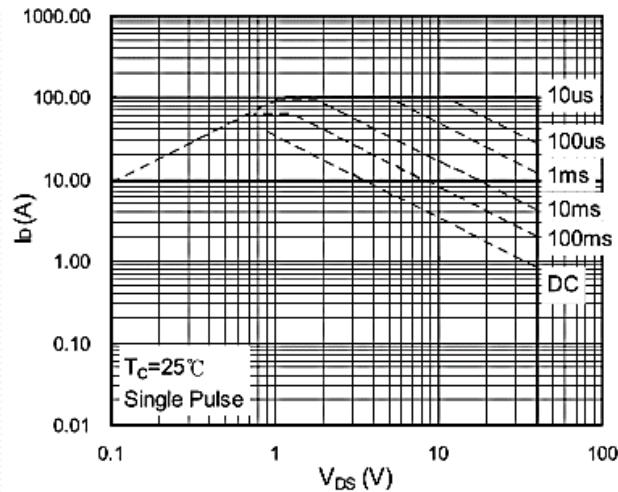
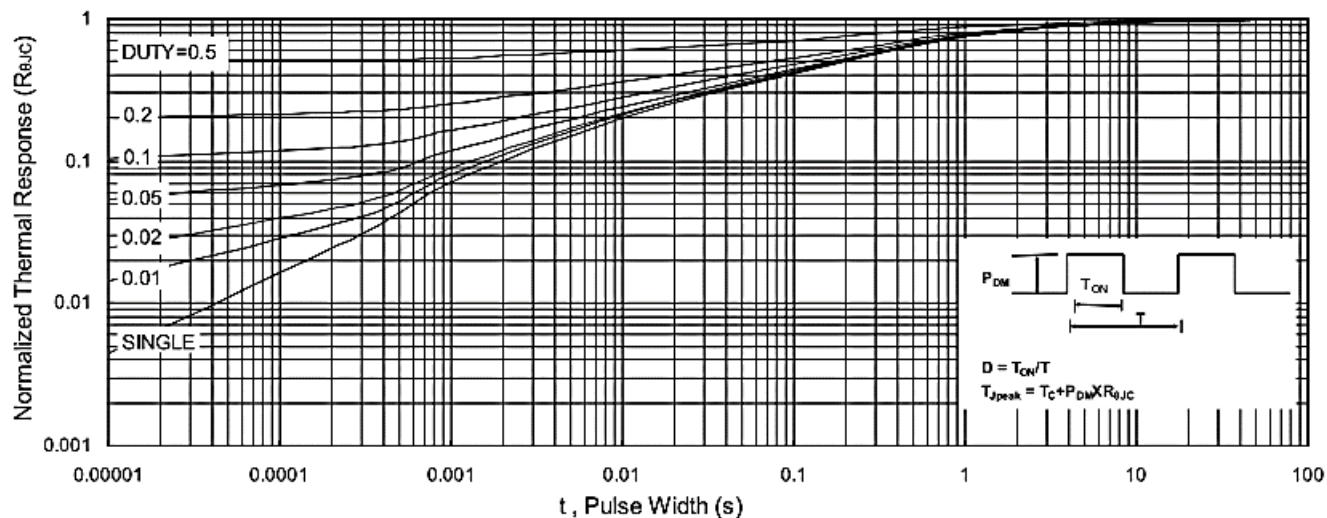
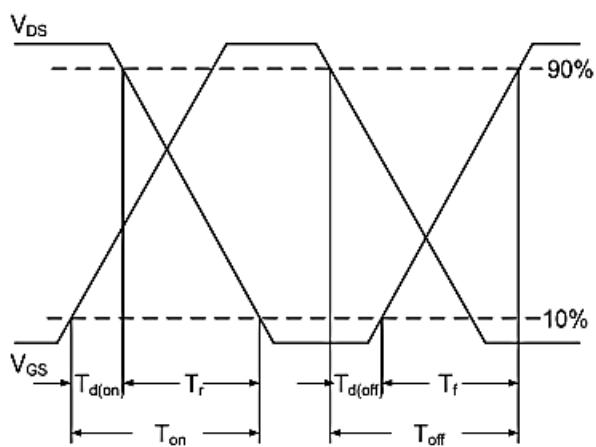
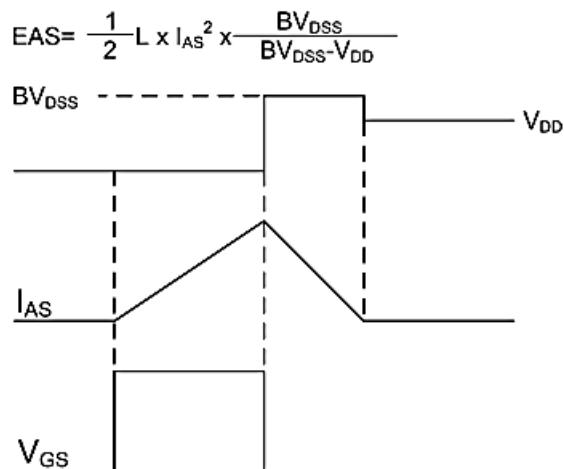
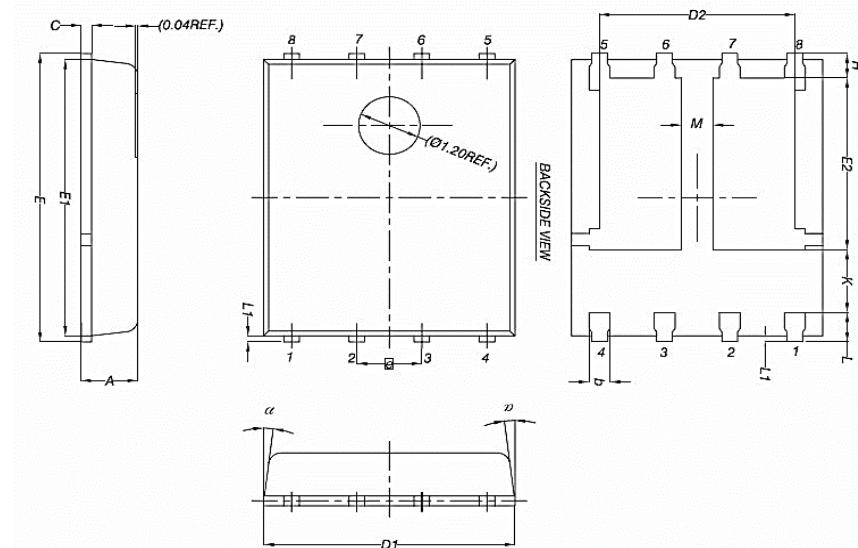


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

40V N+N-Channel Enhancement Mode MOSFET

Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance

Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Switching Waveform


Package Mechanical Data-DFN5*6-8L-JQ Double


Symbol	Common		
	mm		
	Mim	Nom	Max
A	0.90	1.00	1.10
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D1	4.80	4.90	5.00
D2	3.61	3.81	3.96
E	5.90	6.00	6.10
E1	5.70	3.30	3.45
E2	3.38	3.05	3.20
e	1.27BSC		
H	0.41	0.51	0.61
K	1.10	--	--
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
M	0.50	--	--
a	0°	--	12°